



DRAFT AGENDA

Measurement Science & Standards in Forensic Firearms Analysis

July 10-11, 2012

National Institute of Standards and Technology (NIST), 100 Bureau Drive, Gaithersburg, MD 20899 **Room: Building 101 – Lecture Room B**

Webcast Information
To access via phone:
Participation Code:
Web Link:

July 10, 2012

8:30 AM - 9:00 AM	Arrive at NIST Lecture Room B Coffee in NIST Cafeteria
9:00 AM - 9:30 AM 9:30 AM - 10:00 AM	 Welcoming Remarks & Framing the Issue NIST Opening Remarks - Susan Ballou, Program Manager, NIST, Law Enforcement Standards Office, Forensic Science Program Scientific Working Group for Firearms and Toolmarks (SWGGUN)
10:00 AM — 11:00 AM	Current State of Firearms Analysis: Review of the Field including Strengths & Limitations Current Technology Used in the Laboratory – Bill Demuth (ISP) Human Performance in Firearms Analysis – Doug Murphy (FBI) Discussion
11:00 AM - 11:15 AM	BREAK

11:15 AM - 12:00 PM **Manufacturing Processes and Materials** Manufacturing and Machining – Robert Ivester (NIST) Firearms Manufacturer - TO BE INVITED Discussion 12:00 PM - 12:30 PM Introduction to Measurement Science Advances in Firearms Analysis Optical Methods of Surface Measurement – Ted Vorburger (NIST) 12:30 PM - 1:30 PM **LUNCH (NIST Cafeteria - on your own)** 1:30 PM - 3:30 PM **Measurement Science Advances in Firearms Analysis** Confocal Microscopy – Stephen Shaffer (UC Davis) Focus Variation - Franz Helmli (Alicona) - INVITED Interferometric Method for Surface Measurements – Dr. Moosberger – **INVITED** Contact Systems - Marcus Brubaker, PhD (University of Toronto) Infrared for Toolmark Identification - Francine Pookoski (Infrared Identification Inc.) Discussion 3:30 PM - 3:45 PM **BREAK** 3:45 PM - 5:00 PM Advances in Image and Statistical Analysis in Firearms Analysis Comparison and Interpretation of Impressed Marks Left by a Firearm on Cartridge Cases – Christophe Champod (University of Lausanne) Consecutively Matching Stria (CMS) – John Murdock (Private) 3D Surface to 2D Barcode - David Howitt (UC Davis) - INVITED Confocal Analysis - Robert Thompson (NIST) Discussion Please note that all times are in Eastern Time July 11, 2012 8:30 AM - 9:00 AM Arrive at NIST Lecture Room B Coffee in NIST Cafeteria 9:00 AM - 10:15 AM Advances in Image and Statistical Analysis in Firearms Analysis – cont. Striation Density –Wei Chu (Intelligent Automation) Contiguous Matching Cells -- John Song (NIST) Principal Component Analysis and other methods – Nick Petraco (John Jay College of Criminal Justice and The Graduate Center) Discussion

10:15 AM — 11:00 AM	 Measurement Uncertainty & Certainty of Conclusions Uncertainty in Firearms Presentation - James Yen (NIST) , Presentation on Conclusion Statements and How to Introduce Evidence (DNA Example) – Mike Ambrosino (Special Assistant to the US Attorney of DC)
11:00 AM – 11:15 AM	BREAK
11:15 PM - 12:30 PM	Industry Panel on Future of the Discipline: Automated Ballistic Search & Identification Systems • FTI – Alain Beauchamp - INVITED • EVOfinder, - Michael Derenovsky - INVITED • SBC - Yury IIyasov (via Teleconference) • Infrared Identification Inc. – Francine Pookoski • ALIAS – Michael Barrett (Pyramidal Technologies) - INVITED
12:30 PM - 1:30 PM	LUNCH (NIST Cafeteria - on your own)
1:30 PM — 2:30 PM	Role of Standards and Validation to Extend Quantitative Measurement into Practice • Physical Standards, Calibrations and Traceability – Brian Renegar (NIST) • Adopting New Technology Within an Existing Quality Assurance System – Erich Smith (FBI)
2:30 PM - 2:45 PM	BREAK
2:45 PM — 4:45 PM	FACILITATED DISCUSSION: What does the future state of firearms analysis look like? What are the barriers to implementing the future state? Design a roadmap to get there. • Facilitator: Dr. James Hamby • Knowledge Capture: John Paul Jones & SAIC • Discussion Areas include: NAS Statements, Technology, Risk, Research, Validation, Policy, Standards, Legal Admissibility, Cost, etc.
4:45 PM – 5:00 PM	Meeting Summary & Next Steps • John Paul Jones - NIST

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